Unit in mm

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 5 0 8 8

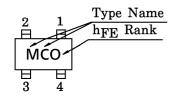
VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

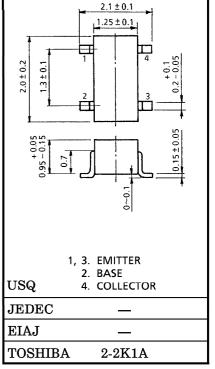
- Low Noise Figure, High Gain.
- NF=1.1dB, $|S_{21e}|^2 = 13dB$ (f=1GHz)

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	20	V
Collector-Emitter Voltage	v_{CEO}	12	V
Emitter-Base Voltage	v_{EBO}	3	V
Base Current	$I_{\mathbf{B}}$	40	mA
Collector Current	$I_{\mathbf{C}}$	80	mA
Collector Power Dissipation	PC	100	mW
Junction Temperature	T_{j}	125	°C
Storage Temperature Range	$T_{ m stg}$	-55~125	°C

MARKING





Weight: 0.006g

MICROWAVE CHARACTERISTICS (Ta = 25°C)

	•	-				
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	$ m f_{T}$	$V_{CE}=10V, I_{C}=20mA$	5	7	_	GHz
Insertion Gain	$ S_{21e} ^2$ (1)	V_{CE} =10V, I_{C} =20mA, f =500MHz	_	18	_	dB
	$ S_{21e} ^2$ (2)	V_{CE} =10V, I_{C} =20mA, f =1GHz	9.5	13	_	uD
Noise Figure	NF (1)	$V_{CE}=10V$, $I_{C}=5mA$, $f=500MHz$	_	1	_	dB
noise rigure	NF (2)	$V_{CE}=10V$, $I_{C}=5mA$, $f=1GHz$	_	1.1	2	և և և

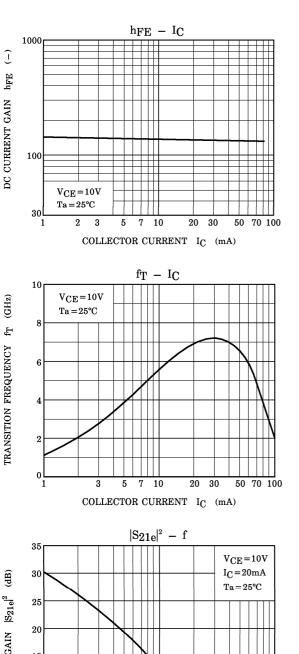
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

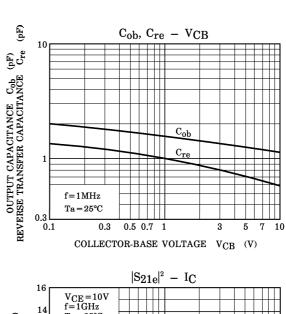
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I_{CBO}	$V_{CB} = 10V, I_{E} = 0$	_	_	1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB}=1V, I_{C}=0$	_	_	1	μ A
DC Current Gain	hFE (Note 1)	$V_{CE} = 10V, I_{C} = 20mA$	80	_	240	_
Output Capacitance	$C_{\mathbf{ob}}$	$V_{CB} = 10V, I_{E} = 0, f = 1MHz$	_	1.1	1.6	pF
Reverse Transfer Capacitance	$\mathrm{C_{re}}$	(Note 2)	_	0.65	1.05	pF

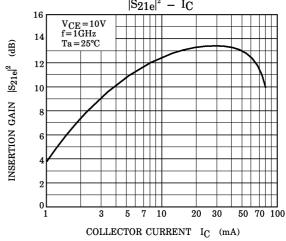
(Note 1) $h_{\mbox{\scriptsize FE}}$ Classification $O:80{\sim}160, Y:120{\sim}240$

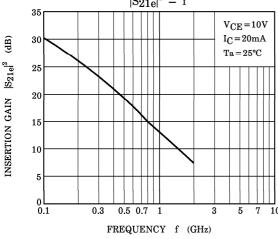
(Note 2) Cre is measured by 3 terminal method with capacitance bridge.

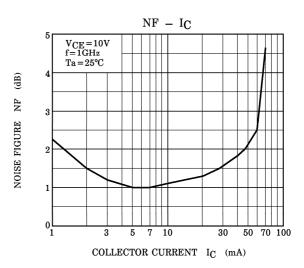
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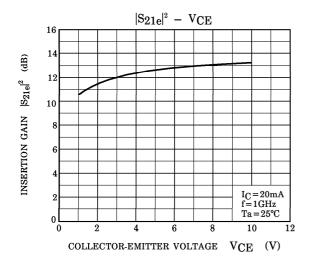


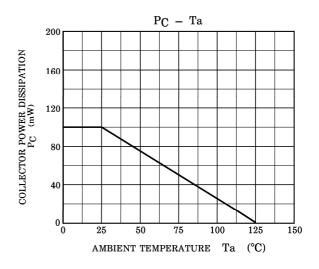












S-Parameter $Z_O = 50\Omega$, $Ta = 25^{\circ}C$ $V_{CE} = 10V$, $I_C = 5mA$

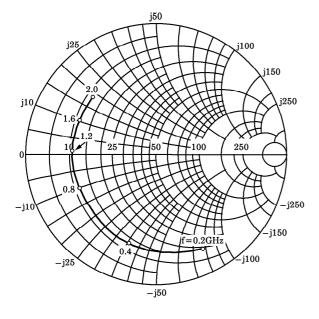
frequency S11		11	S21		S12		S22	
(MHz)	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
200	0.826	-64.3	9.839	139.2	0.056	59.2	0.844	-31.7
400	0.735	-106.8	7.058	115.2	0.083	43.8	0.663	-50.1
600	0.692	-134.4	5.233	99.5	0.094	36.8	0.558	-62.3
800	0.666	-154.3	4.106	88.1	0.100	33.3	0.496	-72.6
1000	0.656	-170.0	3.315	78.9	0.102	32.7	0.458	-81.8
1200	0.653	178.0	2.768	71.3	0.103	33.4	0.429	-90.6
1400	0.649	167.7	2.353	65.4	0.104	36.0	0.407	-99.4
1600	0.655	158.2	2.061	59.6	0.107	39.1	0.393	-107.8
1800	0.653	149.0	1.818	55.3	0.111	42.6	0.378	-115.3
2000	0.654	139.9	1.650	50.7	0.116	46.7	0.367	-121.9

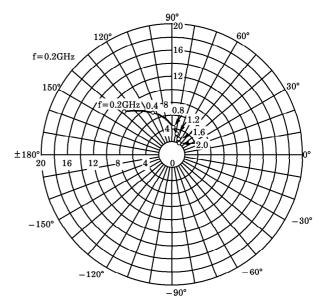
$V_{CE} = 10V, I_{C} = 20mA$

frequency	S11		S21		S12		S22	
(MHz)	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
200	0.747	-87.0	16.492	129.8	0.048	52.1	0.717	-47.1
400	0.675	-130.5	10.431	106.5	0.063	41.8	0.486	-69.1
600	0.648	-154.8	7.298	93.5	0.070	40.8	0.379	-82.0
800	0.636	-170.9	5.547	84.4	0.076	42.0	0.324	-93.0
1000	0.630	176.7	4.423	77.5	0.083	44.7	0.291	-102.7
1200	0.634	166.4	3.660	71.7	0.089	47.7	0.266	-112.1
1400	0.634	157.1	3.125	67.0	0.097	50.8	0.249	-120.8
1600	0.639	148.8	2.741	62.4	0.105	53.2	0.233	-128.9
1800	0.645	139.9	2.451	58.8	0.115	55.6	0.220	-135.8
2000	0.642	131.4	2.233	54.9	0.126	58.1	0.205	-141.2

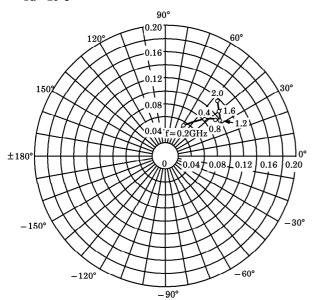
 $\begin{array}{l} S_{11e} \\ V_{CE} = 10V \\ I_{C} = 5 \text{mA} \\ Ta = 25 ^{\circ}\text{C} \\ (Unit: \Omega) \end{array}$

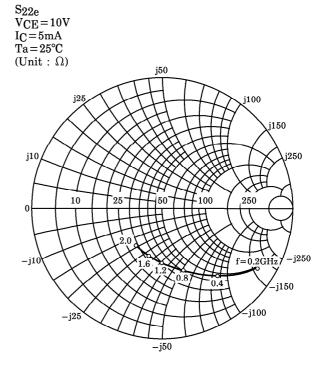






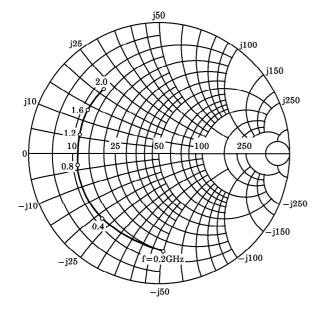
 $\begin{array}{l} S_{12e} \\ V_{CE} \!=\! 10V \\ I_{C} \!=\! 5 \mathrm{mA} \\ Ta \!=\! 25^{\circ}\! C \end{array}$

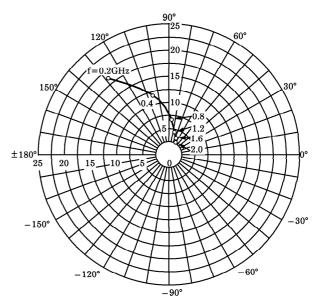




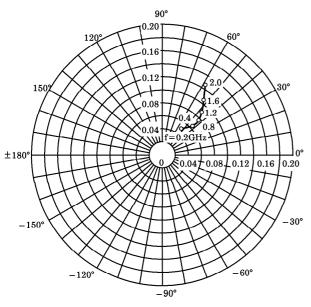
 $\begin{array}{l} S_{11e} \\ V_{CE} = 10V \\ I_{C} = 20 mA \\ Ta = 25 ^{\circ}C \\ (Unit: \Omega) \end{array}$

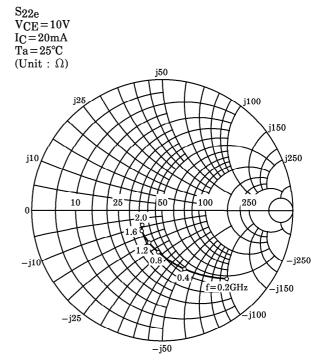






 $\begin{array}{l} {\rm S_{12e}} \\ {\rm V_{CE}} \! = \! 10{\rm V} \\ {\rm I_{C}} \! = \! 20{\rm mA} \\ {\rm Ta} \! = \! 25^{\circ}{\rm C} \end{array}$





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